TOSHIBA Transistor Silicon PNP Epitaxial Type

TPC6602

High-Speed Switching Applications DC-DC Converter Applications Strobe Applications

- High DC current gain: hFE = 200 to 500 (IC = -0.2 A)
- Low collector-emitter saturation voltage: V_{CE} (sat) = -0.19 V (max)
- High-speed switching: $t_f = 25 \text{ ns (typ.)}$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V_{CBO}	-20	V	
Collector-emitter voltage		V_{CEO}	-10	V	
Emitter-base voltage		V _{EBO}	-7	V	
Collector current	DC	Ic	-2.0	А	
	Pulse	I _{CP}	-3.5		
Base current		lΒ	-200	mA	
Collector power dissipation	t = 10 s	P _C	1.6	W	
	DC	(Note)	0.8		
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	–55∼150	°C	

Note: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm^2)

Unit: mm Unit: mm 1. Collector (C) 4. Emitter (E) 2. Collector (C) 5. Collector (C) 3. Base (B) 6. Collector (C) JEDEC — JEITA — TOSHIBA 2-3T1

Weight: 0.011 g (typ.)

Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off of	current	I _{CBO}	$V_{CB} = -20 \text{ V}, I_E = 0$	_	_	-100	nA
Emitter cut-off cu	rrent	I _{EBO}	$V_{EB} = -7 \text{ V, } I_{C} = 0$	_	_	-100	nA
Collector-emitter	breakdown voltage	V (BR) CEO	$I_C = -10 \text{ mA}, I_B = 0$	-10	_	_	V
DC current gain		h _{FE} (1)	$V_{CE} = -2 \text{ V}, I_{C} = -0.2 \text{ A}$	200	_	500	
		h _{FE} (2)	$V_{CE} = -2 \text{ V}, I_{C} = -0.6 \text{ A}$	125	_	_	
Collector-emitter	saturation voltage	V _{CE (sat)}	$I_C = -0.6 \text{ A}, I_B = -0.02 \text{ A}$	_	_	-0.19	V
Base-emitter saturation voltage		V _{BE (sat)}	$I_C = -0.6 \text{ A}, I_B = -0.02 \text{ A}$	_	_	-1.10	V
Collector output capacitance		C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$	_	12	_	pF
Switching time	Rise time	t _r	See Figure 1 circuit diagram.	_	50	_	
	Storage time	t _{stg}	$V_{CC} \simeq -6 \text{ V}, R_L = 10 \Omega$		115	_	ns
	Fall time	t _f	$I_{B1} = -I_{B2} = -20 \text{ mA}$	_	25	_	

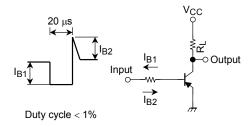
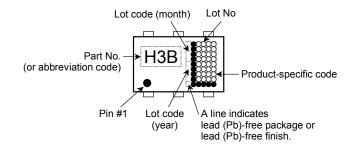


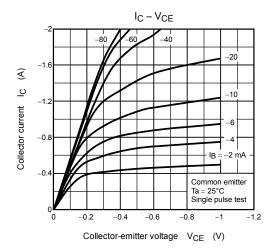
Figure 1 Switching Time Test Circuit & Timing Chart

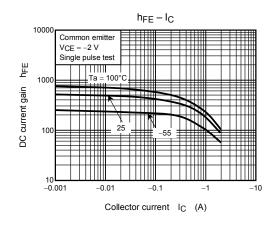
Circuit Configuration

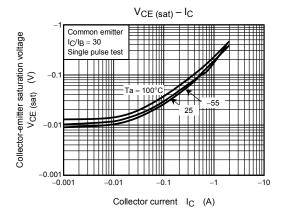
6 5 4

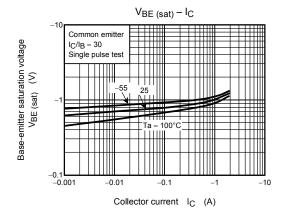
Marking

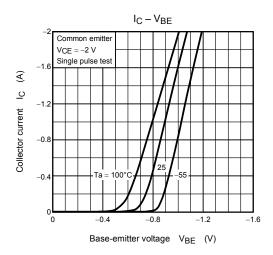




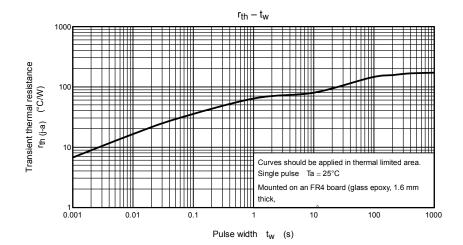


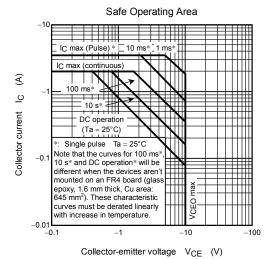






3 2004-07-07





RESTRICTIONS ON PRODUCT USE

030619EAA

- The information contained herein is subject to change without notice.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of TOSHIBA or others.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
 In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- TOSHIBA products should not be embedded to the downstream products which are prohibited to be produced and sold, under any law and regulations.